

# Quiz - 3 Solutions

EE 207: Electronic Devices and Circuits

Quiz 3 08/11/2018

Maximum marks: 11, Time: 1 hr 15 min

Make reasonable assumptions and state them clearly.

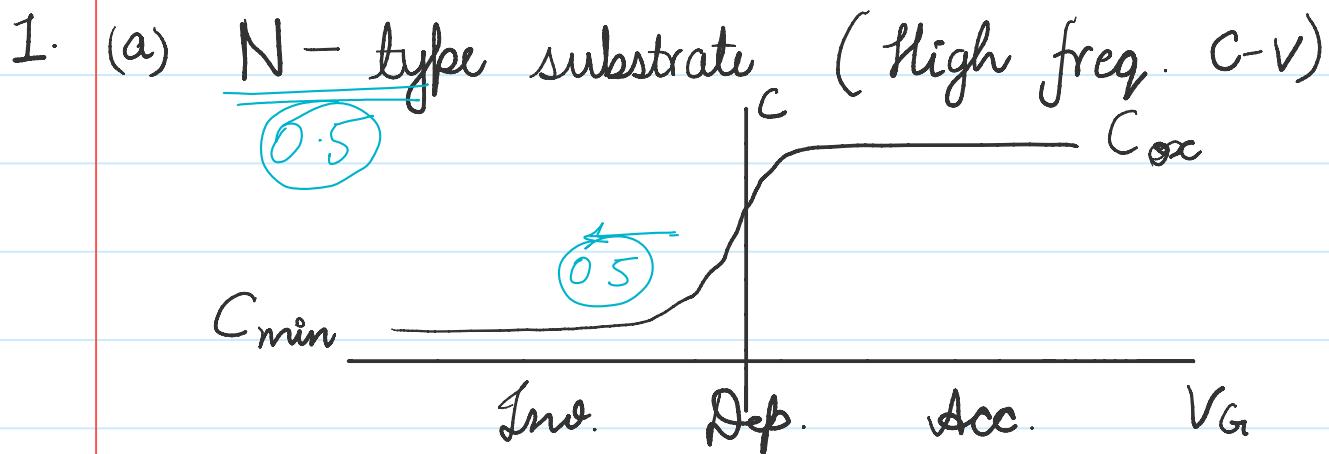
Important constants:  $k=8.62 \times 10^{-5} \text{ eV/K}$ ,  $q=1.602 \times 10^{-19} \text{ Coulomb}$ ,  $k_{\text{silicon-dioxide}}=3.9$ ,  $\epsilon_0=8.85 \times 10^{-14} \text{ F/cm}$ ,  $k_{\text{silicon}}=11.9$

1. (1+1+2+1+2+1+1=9 Marks) An ideal metal-SiO<sub>2</sub>-Si MOS capacitor is operated at T=300 K,  $x_0=0.1 \text{ um}$ ,  $N_D=2 \times 10^{15} \text{ cm}^{-3}$  and gate area  $A_G=10^{-3} \text{ cm}^2$ .

- (a) Sketch the general shape of the high frequency C-V characteristic of this device.
- (b) Determine the maximum high-frequency capacitance of this device.
- (c) Determine the minimum high-frequency capacitance of this device employing the delta-depletion approximation.
- (d) If  $V_G=V_T$ , determine  $\phi_s$ .
- (e) Compute  $V_T$ .
- (f) Draw the energy band diagram corresponding to gate bias such that  $\phi_s = 3\phi_F/2$ .
- (g) Draw the block charge diagram corresponding to gate bias such that  $\phi_s = 5\phi_F/2$ .

2. (1+1=2 Marks) Consider an MOS capacitor on a p-type silicon substrate. The oxide capacitance is  $2 \times 10^{-7} \text{ F/cm}^2$ , the metal-semiconductor work function difference is -1 V and a positive charge  $Q_F = 8 \times 10^{-8} \text{ C/cm}^2$  resides at the interface. There is no charge in interface states.

- (a) Calculate the flat-band voltage
- (b) Is there an electric field in the oxide? If yes, what is its magnitude?



(b)  $C_{max}$  in accumulation

$$C_{max} = C_{ox} \times A_G$$

$$\begin{aligned} &= \frac{\epsilon_{ox}}{t_{ox}} \times A_G \\ &= \frac{8.85 \times 10^{-14} \text{ F/cm} \times 3.9}{0.1 \times 10^{-4} \text{ cm}} \times 10^{-3} \text{ cm}^2 \\ &= \underline{\underline{34.5 \text{ pF}}} \end{aligned}$$

c) Under  $\Delta$ -dep approximation, the semiconductor depletion width is maximum at the onset of inversion  $\phi_s = 2\phi_f$

$$\phi_f = \frac{kT}{q} \ln \left( \frac{N_D}{n_i} \right)$$

At room temperature,  $\frac{kT}{q} \approx 26 \text{ mV}$

$$\phi_f = 26 \ln \left( \frac{2 \times 10^{15}}{10^{10}} \right) \text{ mV} \approx 0.32 \text{ V}$$

$$C_{min} = \frac{C_{ox} A_G}{1 + \frac{k_{ox}}{k_s} \frac{W_{dep}}{t_{ox}}} \quad (0.5)$$

$$W_{dep} = \sqrt{\frac{2 \epsilon_s (2\phi_f)}{q N_D}} \quad (0.5)$$

$$= \sqrt{\frac{2 \times 11.9 \times 8.85 \times 10^{-12} \times 0.64}{1.6 \times 10^{-19} \times 2 \times 10^{21}}} \text{ m}$$

$$= \underline{0.65} \text{ } \mu\text{m} \quad (0.5)$$

$$C_{min} = \frac{34.5}{1 + \frac{3.9}{11.9} \times \frac{0.65}{0.1}} \text{ pF} \approx \underline{11 \text{ pF}} \quad (0.5)$$

(d) If  $V_{G2} = V_T$ ;  $|\phi_s| = |2\phi_f| = \underline{0.64 \text{ V}} \quad (0.5)$

$\phi_s$  will be negative. (0.5)

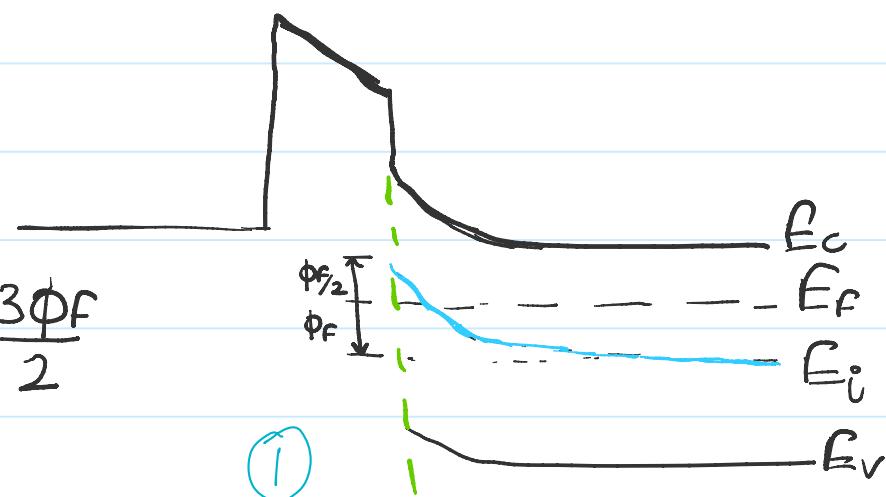
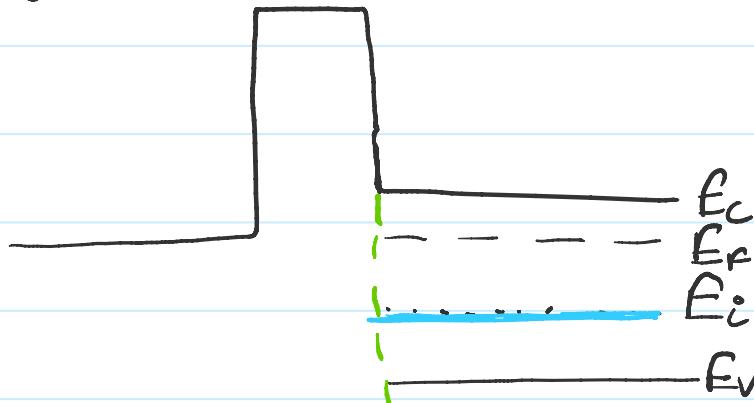
(e) Assuming  $\phi_{MS} = 0$ ,

$$V_T = - \left( 2\phi_F + \frac{qN_D W d\phi}{C_{ox}} \right) \quad \textcircled{1}$$

$$= - \left( 0.64 + \frac{1.6 \times 10^{19} \times 2 \times 10^{15} \times 0.65 \times 10^{-4}}{34.5 \times 10^{-12} \times 10^3} \right) V$$

$$= - 1.24 \text{ V} \quad \textcircled{1}$$

(f) Starting from  $\phi_S = 0$ ,



$$\phi_S = \frac{3\phi_F}{2}$$

$$(g) \quad \phi_s = 5\phi_F/2$$

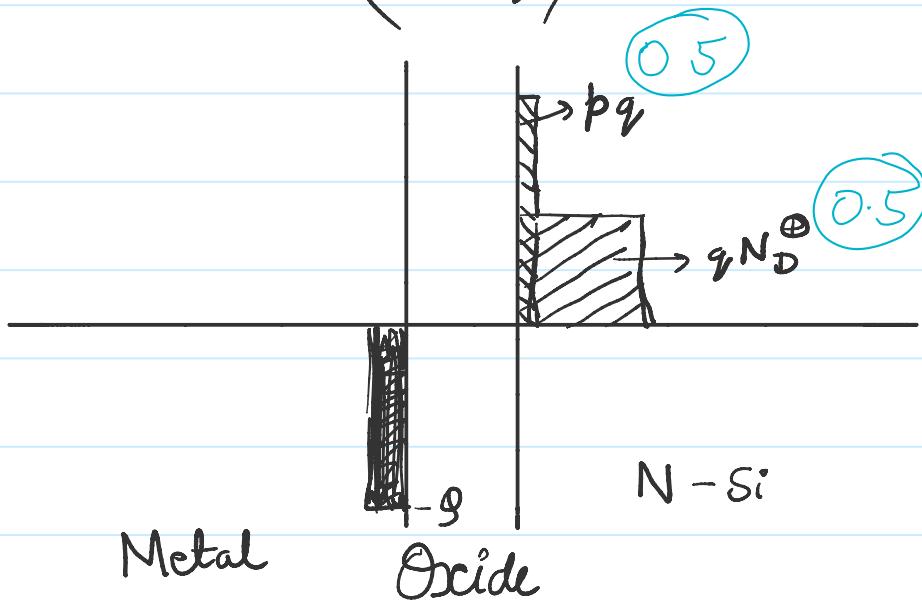
Inversion hole charge density

$$p = n_i e^{((5\phi_F/2 - \phi_F)/kT/q)}$$

$$= n_i e^{(3\phi_F/2 kT/q)}$$

$$e^{\phi_F/kT/q} \Rightarrow N_D/n_i \text{ (known)}$$

$$p = n_i \left( \sqrt{\frac{N_D}{n_i}} \right)^3 = 9 \times 10^{17} / \text{cm}^3$$



Solution 2:

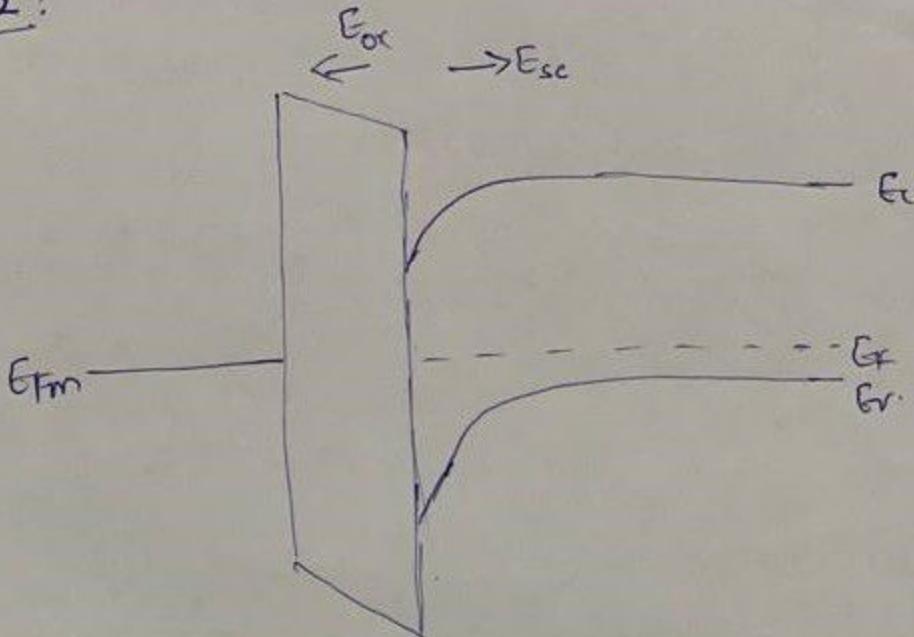


Fig: Band diagram in Equilibrium.

Note that due to presence of  $\sigma_F = 8 \times 10^{-8} \text{ C/cm}^2$  @ interface, the E-field is in opposite directions around the interface.

$$(a) \phi_{ms} = \phi_m - \phi_s = -1 \text{ eV}$$

$$C_{ox} = 2 \times 10^{-7} \text{ F/cm}^2$$

$V_{FB} \Rightarrow V_G$  at which bands in semiconductor are flat.

Now,  $V_{FB} = \frac{\phi_{ms}}{q} - \frac{\sigma_F}{C_{ox}} = \left( -1 - \frac{8 \times 10^{-8}}{2 \times 10^{-7}} \right) V$

$$\Rightarrow V_{FB} = -1.4 V$$

(b) @ interface  $D_{ox} - D_{si} = \sigma_F$ ;  $D$ : normal dielectric displacement

at Flat band  $D_{si} = \epsilon_{si} E_{si} = 0 \therefore E_{si} = 0$

$$\Rightarrow D_{ox} = \epsilon_{ox} E_{ox} = \sigma_F \Rightarrow E_{ox} = \frac{\sigma_F}{\epsilon_{ox}}$$

Direction: (towards gate)

$$\Rightarrow E_{ox} = 2.317 \times 10^5 \text{ V/cm}$$